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Atomic Force Microscope Scanning Head with 3-Dimensional
Orthogonal Scanning to eliminate the curved coupling

Yushu Shi , Wei Li , Sitian Gao , Mingzhen Lu , Xiaodong Hu

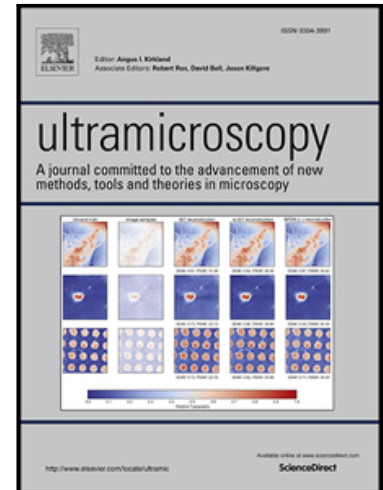
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Highlights

- A novel probe scanning atomic force microscopy with 3 dimensional planar scanning has been developed.
- New optical lever amplification optical path is designed to compensate the shift of beam spot during scanning.
- Compared with tube scanning AFM, the scanning head reduces the curvature distortion significantly.

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